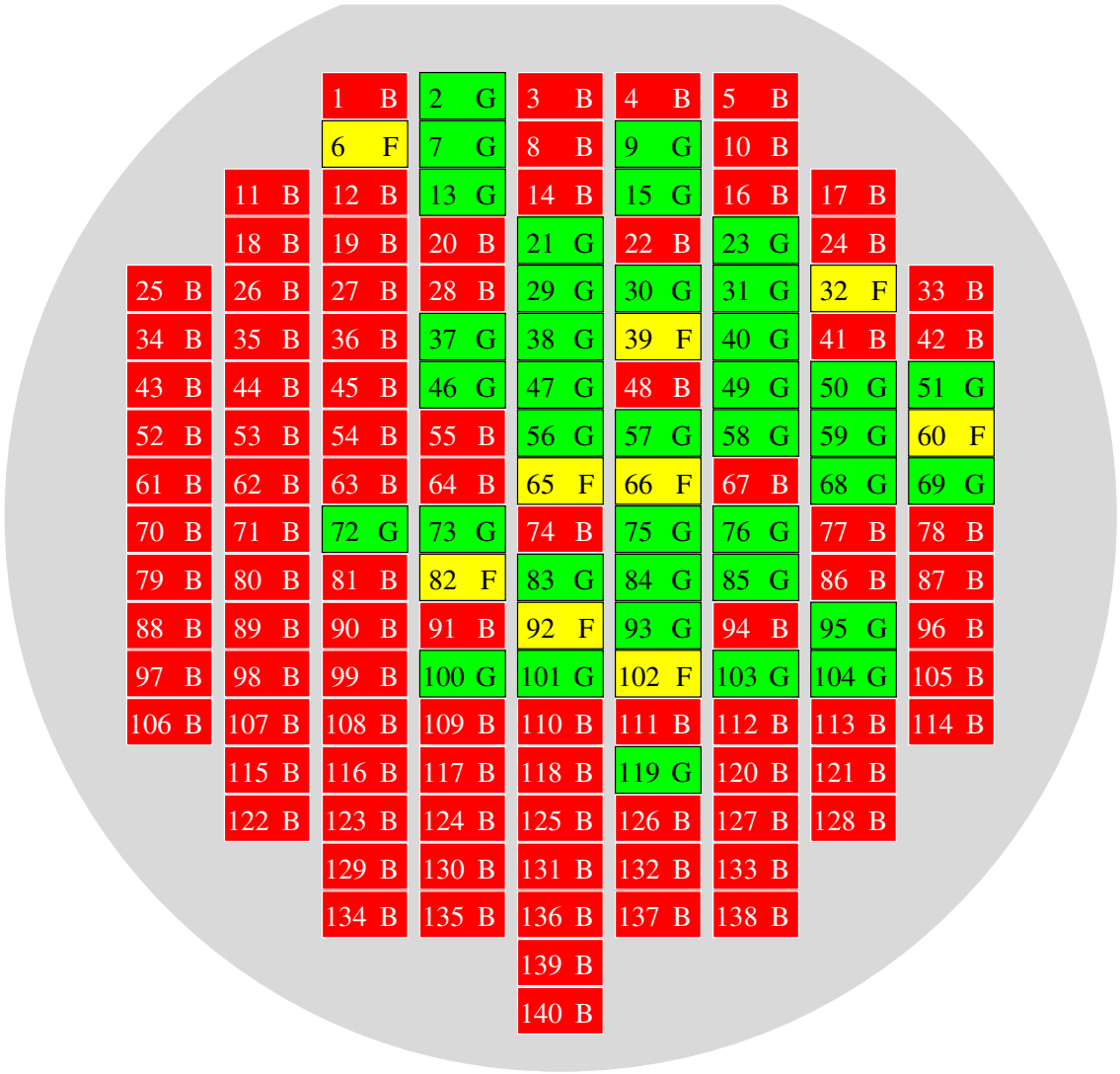
Die quality map for wafer 157 s/n: Y21316-08-18

Date: 06/22/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged